ELECTRONIC COMPONENT TEST METHOD TAKING ACCOUNT OF THE DRIFT IN THE MEAN

ABSTRACT OF THE DISCLOSURE

A method for the testing of electronic components, proposing an optimisation of a duration for the tests of this method, consists in choosing an earliest possible measurement date (Dm) with respect to an initial testing date (Do). According to this method, this earliest possible measurement date is chosen by considering statistical images (IS) obtained on a population of components (P1, P2) and by comparing these statistical images with one another by means of a criterion. This criterion takes account of a mean and an amplitude of the responses given by the test population during iterations of a same test with different measurement dates.

Figure 2.